

TOSHIBA GTR MODULE SILICON N CHANNEL IGBT

MG30V2YS40

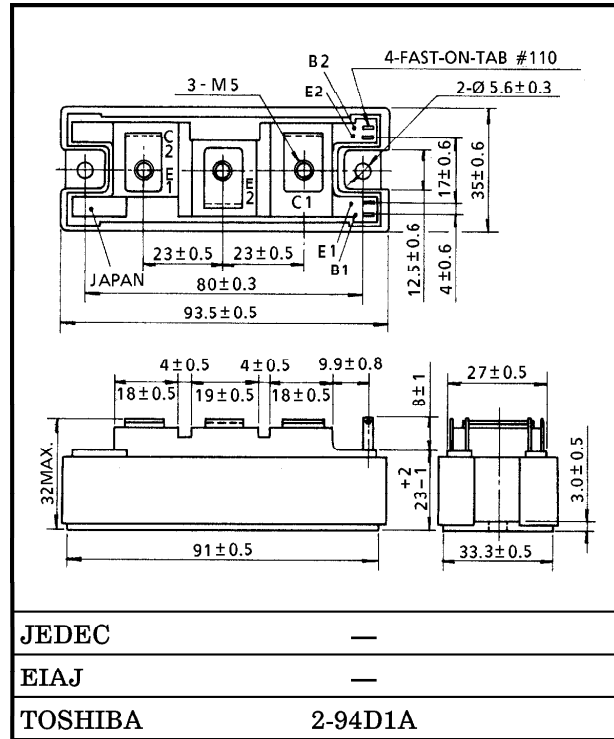
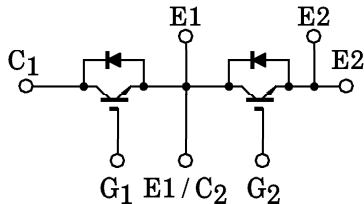
HIGH POWER SWITCHING APPLICATIONS

Unit in mm

MOTOR CONTROL APPLICATIONS

- The Electrodes are Isolated from Case.
- High Input Impedance
- Includes a Complete Half Bridge in One Package.
- Enhancement-Mode
- High Speed : $t_f = 1.5 \mu s$ (Max.) ($I_C = 30A$)
 $t_{rr} = 0.3 \mu s$ (Max.) ($I_F = 30A$)

EQUIVALENT CIRCUIT



Weight : 202g (TYP.)

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Emitter Voltage	V_{CES}	1700	V
Gate-Emitter Voltage	V_{GES}	± 20	V
Collector Current	DC	I_C	30
	1ms	I_{CP}	60
Forward Current	DC	I_F	30
	1ms	I_{FM}	60
Collector Power Dissipation (Tc = 25°C)	P_C	500	W
Junction Temperature	T_j	150	°C
Storage Temperature Range	T_{stg}	-40~125	°C
Isolation Voltage	V_{Isol}	4000 (AC 1 min.)	V
Screw Torque (Terminal / Mounting)	—	3 / 3	N·m

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ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		I_{GES}	$V_{GE} = \pm 20V, V_{CE} = 0$	—	—	± 50	nA
Collector Cut-off Current		I_{CES}	$V_{CE} = 1700V, V_{GE} = 0$	—	—	0.5	mA
Gate-Emitter Cut-off Voltage		$V_{GE} (off)$	$I_C = 30mA, V_{CE} = 5V$	4.0	—	8.0	V
Collector-Emitter Saturation Voltage		$V_{CE} (sat)$	$I_C = 30A, V_{GE} = 15V$	—	3.2	4.5	V
Input Capacitance		C_{ies}	$V_{CE} = 10V, V_{GE} = 0, f = 1MHz$	—	4400	—	pF
Switching Time	Turn-on Delay Time	$t_d (on)$	Inductive Load $V_{CC} = 900V$ $I_C = 30A$ $V_{GE} = \pm 15V$ $R_G = 24\Omega$ (Note 1)	—	0.1	—	μs
	Rise Time	t_r		—	0.1	—	
	Turn-on Time	t_{on}		—	0.5	—	
	Turn-off Delay Time	$t_d (off)$		—	0.4	—	
	Fall Time	t_f		—	0.5	1.5	
	Turn-off Time	t_{off}		—	1.0	—	
Forward Voltage		V_F	$I_F = 30A, V_{GE} = 0$	—	3.2	4.5	V
Reverse Recovery Time		t_{rr}	$I_F = 30A, V_{GE} = -15V$ $di / dt = 500A / \mu s$ (Note 1)	—	0.1	0.3	μs
Thermal Resistance		$R_{th (j-c)}$	Transistor Stage	—	—	0.25	$^{\circ}C / W$
			Diode Stage	—	—	1.0	

Note 1 Switching Time and Reverse Recovery Time Test Circuit & Timing Chart

